

Notice of References Cited	Application/Control No. 09/900,779	Applicant(s)/Patent Under Reexamination BRAND ET AL.	
	Examiner Ayal I. Sharon	Art Unit 2123	Page 1 of 4

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	Examiner Ayal I. Sharon	Art Unit 2123	Page 2 of 4

U.S. PATENT DOCUMENTS

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Notice of References Cited	Application/Control No. 09/900,779	Applicant(s)/Patent Under Reexamination BRAND ET AL.	
	Examiner Ayal I. Sharon	Art Unit 2123	Page 3 of 4

U.S. PATENT DOCUMENTS

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	A	US-			
	B	US-			
	C	US-			
	D	US-			
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	Examiner Ayal I. Sharon	Art Unit 2123	Page 4 of 4

U.S. PATENT DOCUMENTS

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	D	US-			
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